

# ECE520 – VLSI Design

## Lecture 9: Design Rules

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# *Review of Last Lecture*

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## **Interconnect Manufacturing Process**

- **Back-end Process (Conventional)**
- **Back-end Process (Modern – Dual Damascene)**

## **Interconnect Modeling**

- **Parasitic Capacitance**
- **Parasitic Resistance**
- **Parasitic Inductance**
- **Delay Estimation Techniques**

# *Today's Lecture*

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- ❑ Review of output resistance of an inverter
- ❑ Overview of Design Rules
  - What are design rules?
  - Why have design rules?
  - Typical design rules

# *What Are Design Rules?*

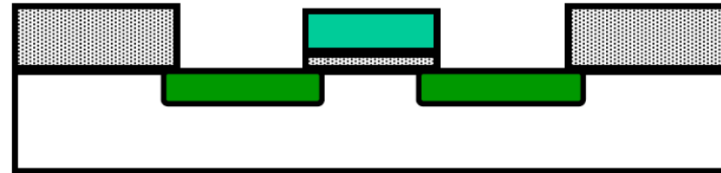
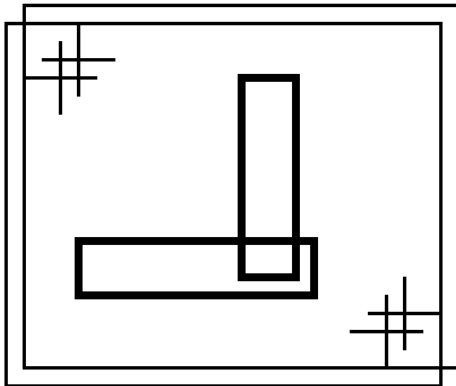
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- ❑ **Interface between the circuit designer and process engineer**
- ❑ **Guidelines for constructing process masks**
- ❑ **Unit dimension: minimum feature size (transistor gate length)**
  - **scalable design rules: lambda parameter**
  - **absolute dimensions: micron rules**
- ❑ **Rules constructed to ensure that design works even when small fab errors (within some tolerance) occur**
- ❑ **A complete set includes**
  - **set of layers**
  - **intra-layer: relations between objects in the same layer**
  - **inter-layer: relations between objects on different layers**

# Why Have Design Rules?

- ❑ To be able to tolerate some level of fabrication errors such as
  - Mask misalignment
  - Dust
  - Process parameters (e.g., lateral diffusion)
  - Rough surfaces



# Typical CMOS Process Layers

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## Layers:

**N-Well**  
**Active Area**  
**Select (n+,p+)**  
**Polysilicon**  
**Metal1**  
**Metal2**  
**Contact To Poly**  
**Contact To Diffusion**  
**Via**









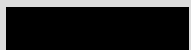
## **Points:**

- N-well process p-type wafer (no p-well)
- Active area determines where transistors may go
- Poly overlapping with active = transistor
- Select is where n+ and p+ ion implantation occurs; it can be used to place an opposite type region (e.g., put p+ select within n-well to create a p+ well plug, more later)
- All contacts/vias are the same size (eases processing)
- Advanced technology is more complex and has more layers (e.g. Thick Oxide, Thin Oxide, VT\_high, VT\_low, LI, etc.)

# CMOS Process Layers in Layout Tools

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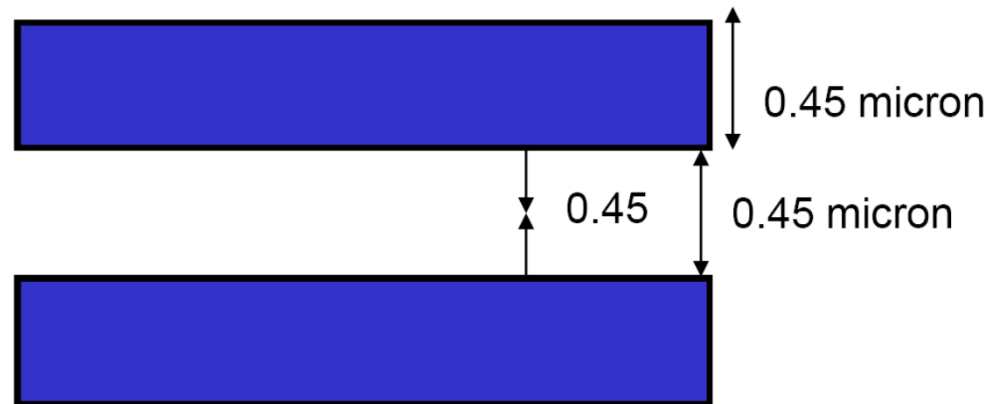
Layer	Color	Representation
Well (p,n)	Yellow	
Active Area (n+,p+)	Green	
Select (p+,n+)	Green	
Polysilicon	Red	
Metal1	Blue	
Metal2	Magenta	
Contact To Poly	Black	
Contact To Diffusion	Black	
Via	Black	

# *Intra-Layer Design Rule Origins*

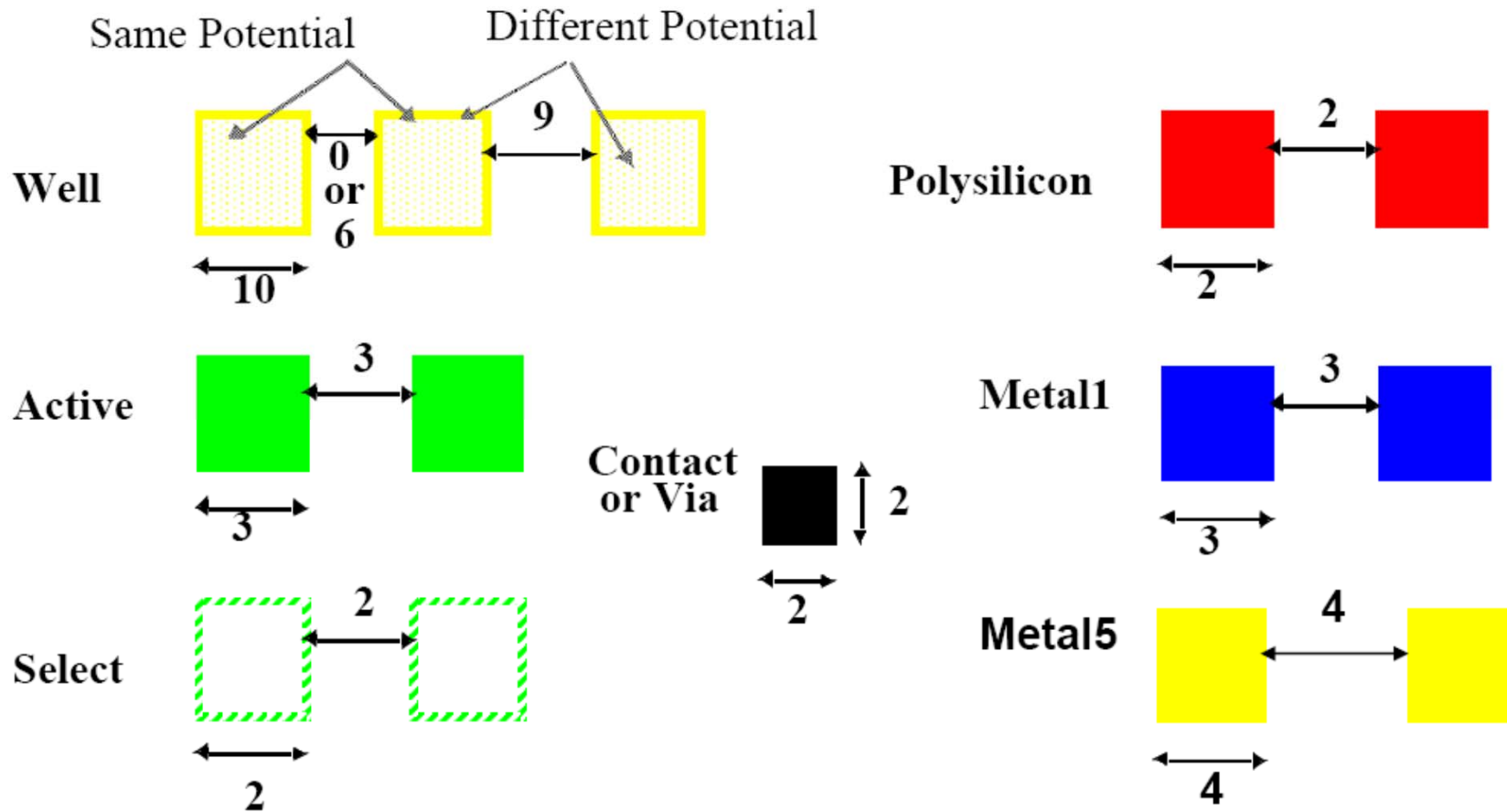
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- ❑ **Minimum dimensions (e.g., widths) of objects on each layer to maintain that object after fab**
  - minimum line width is set by the resolution of the patterning process (photolithography)
- ❑ **Minimum spaces between objects (that are not related) on the same layer to ensure they will not short after fab**

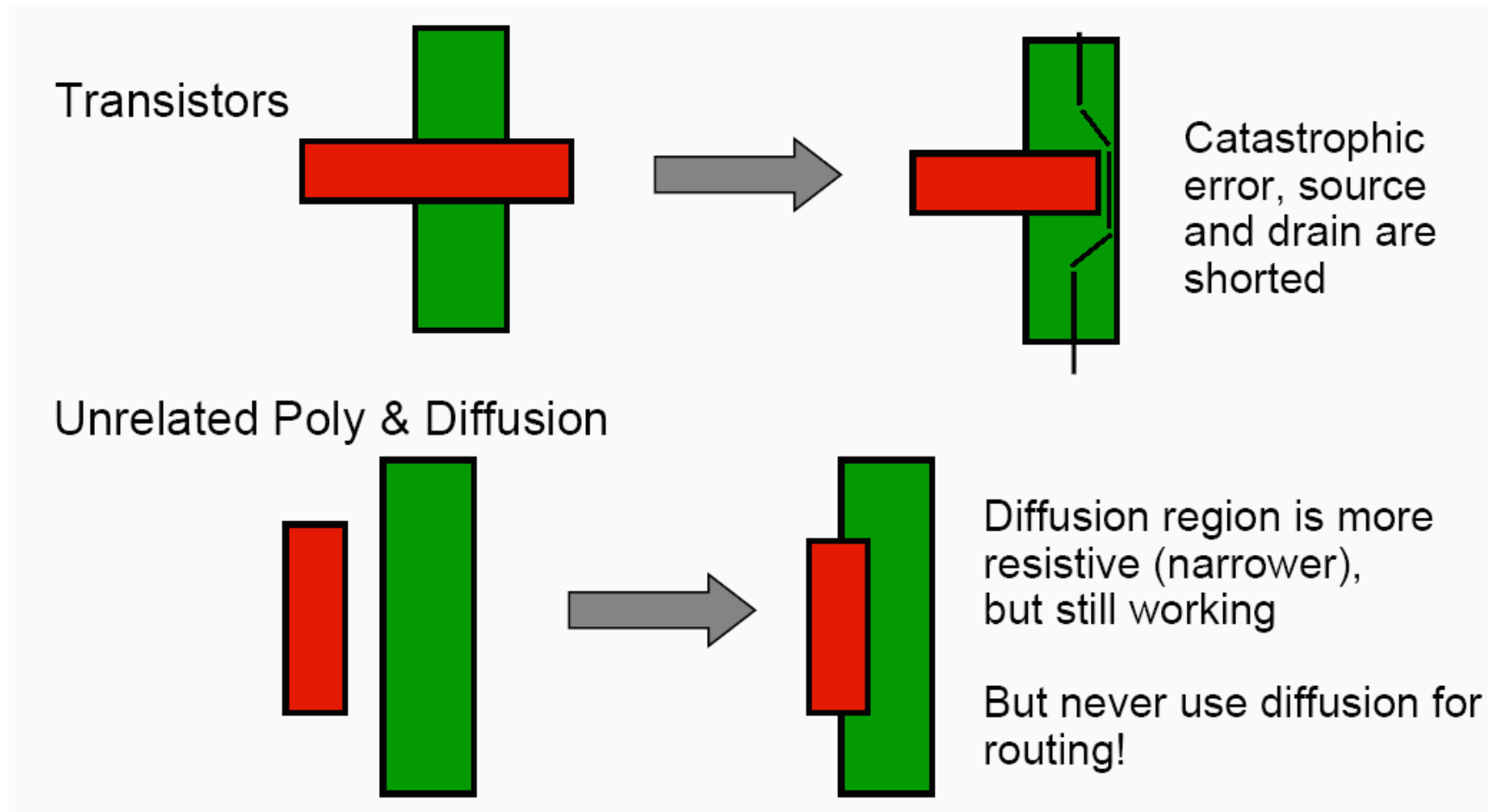


# Intra-Layer Design Rules



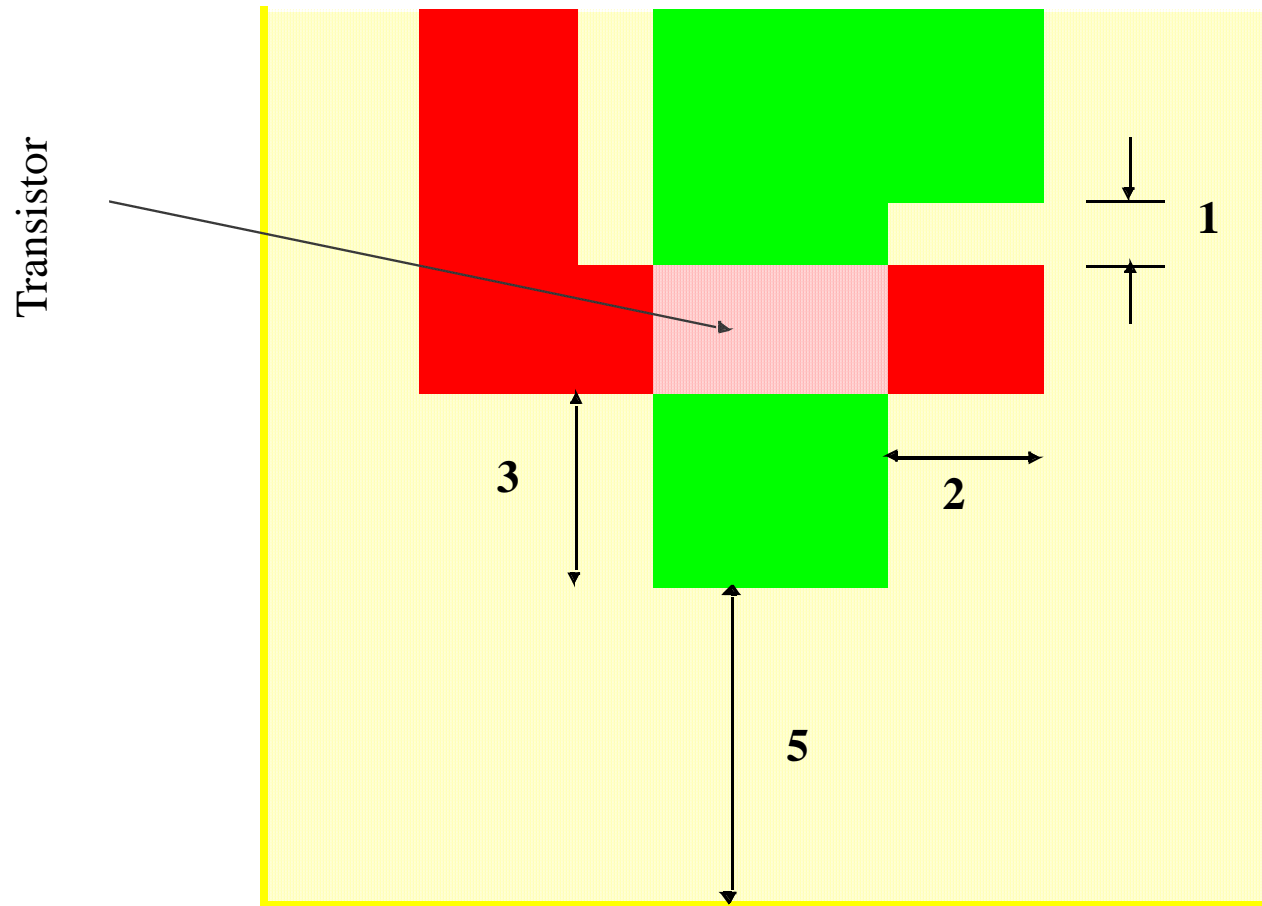
# Inter-Layer Design Rule Origins

- ❑ Transistor rules – transistor formed by overlap of diffusion (also called active) and poly layers

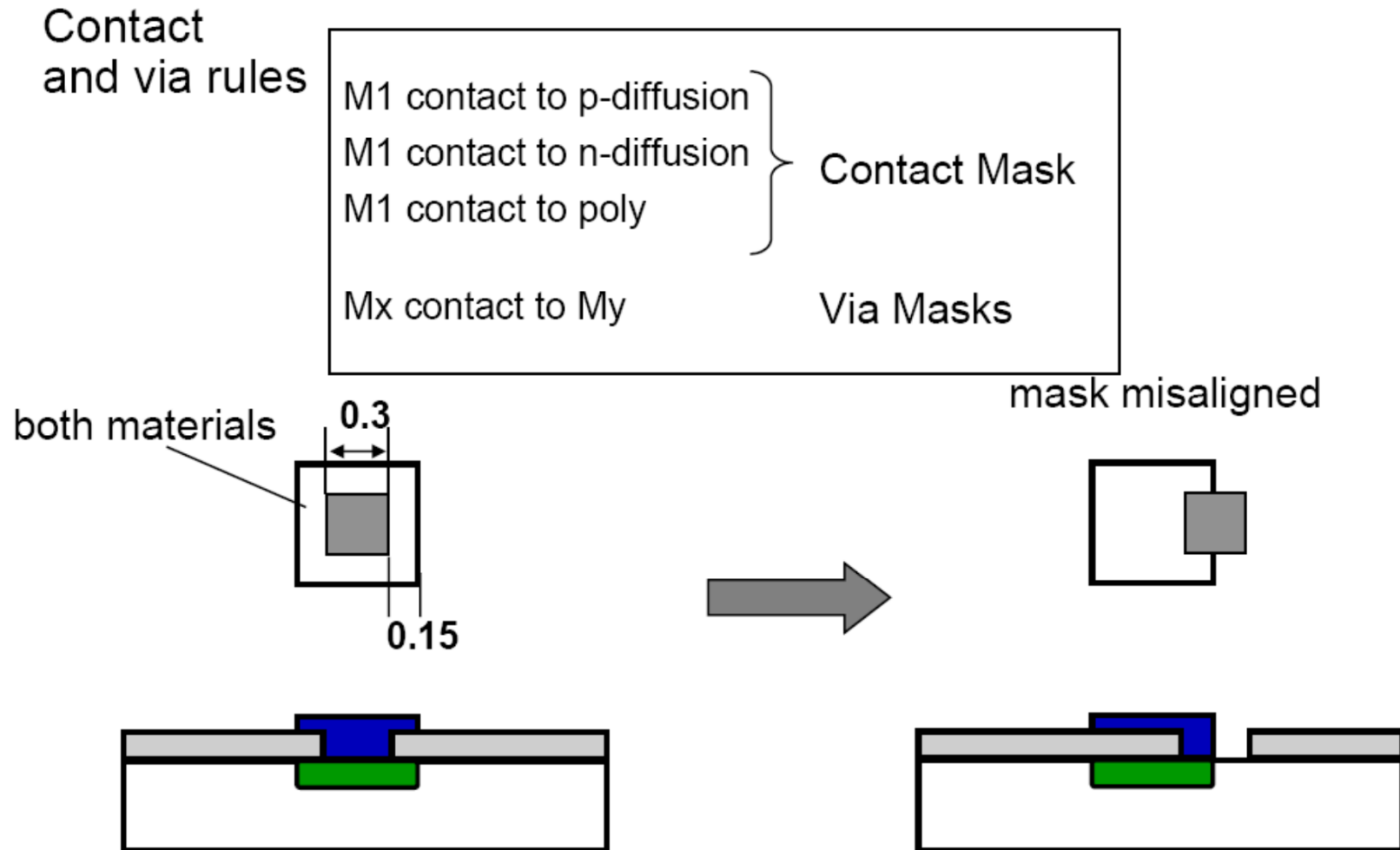


# Transistor Layout

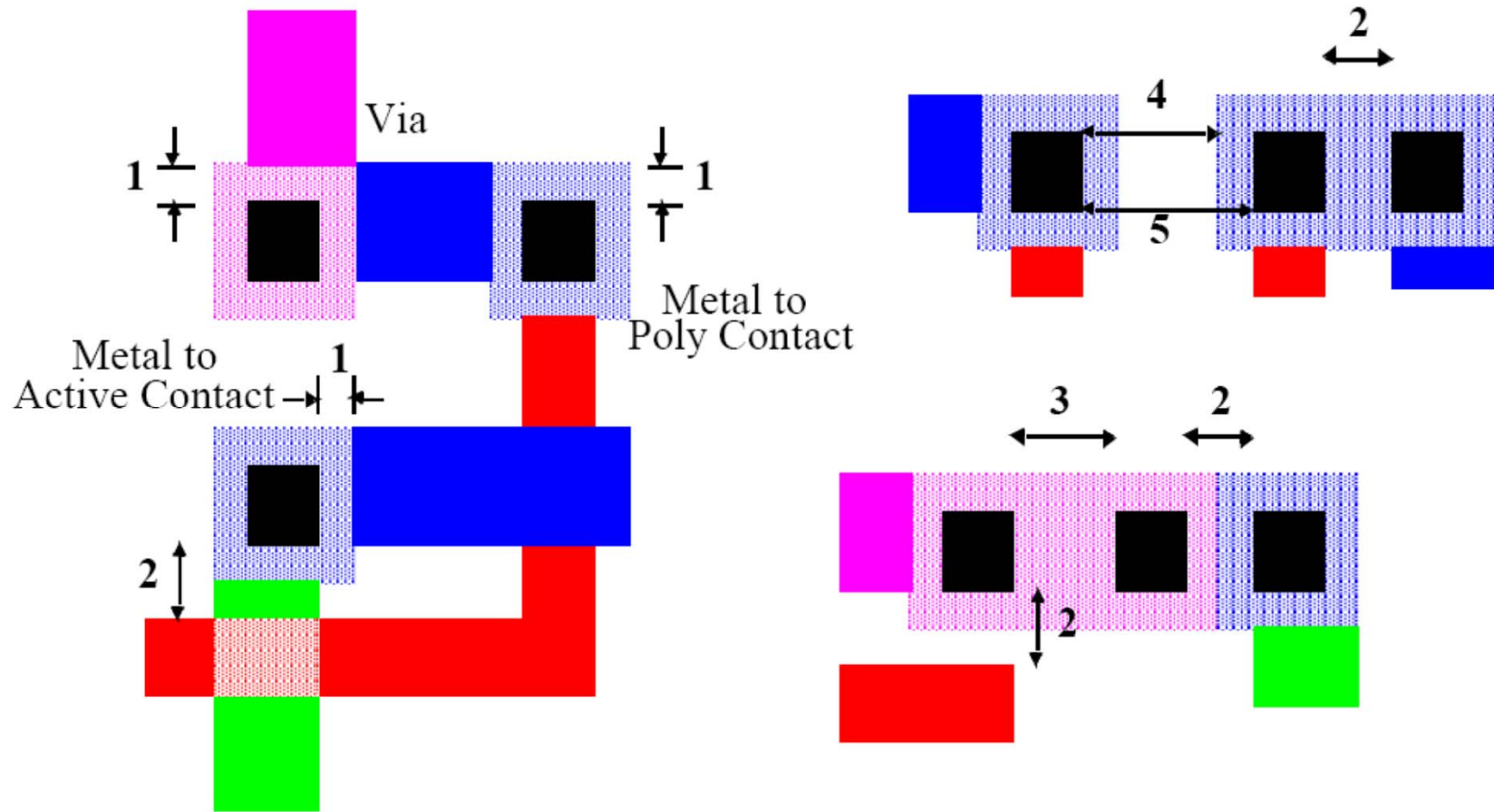
- We will almost always use minimum L device



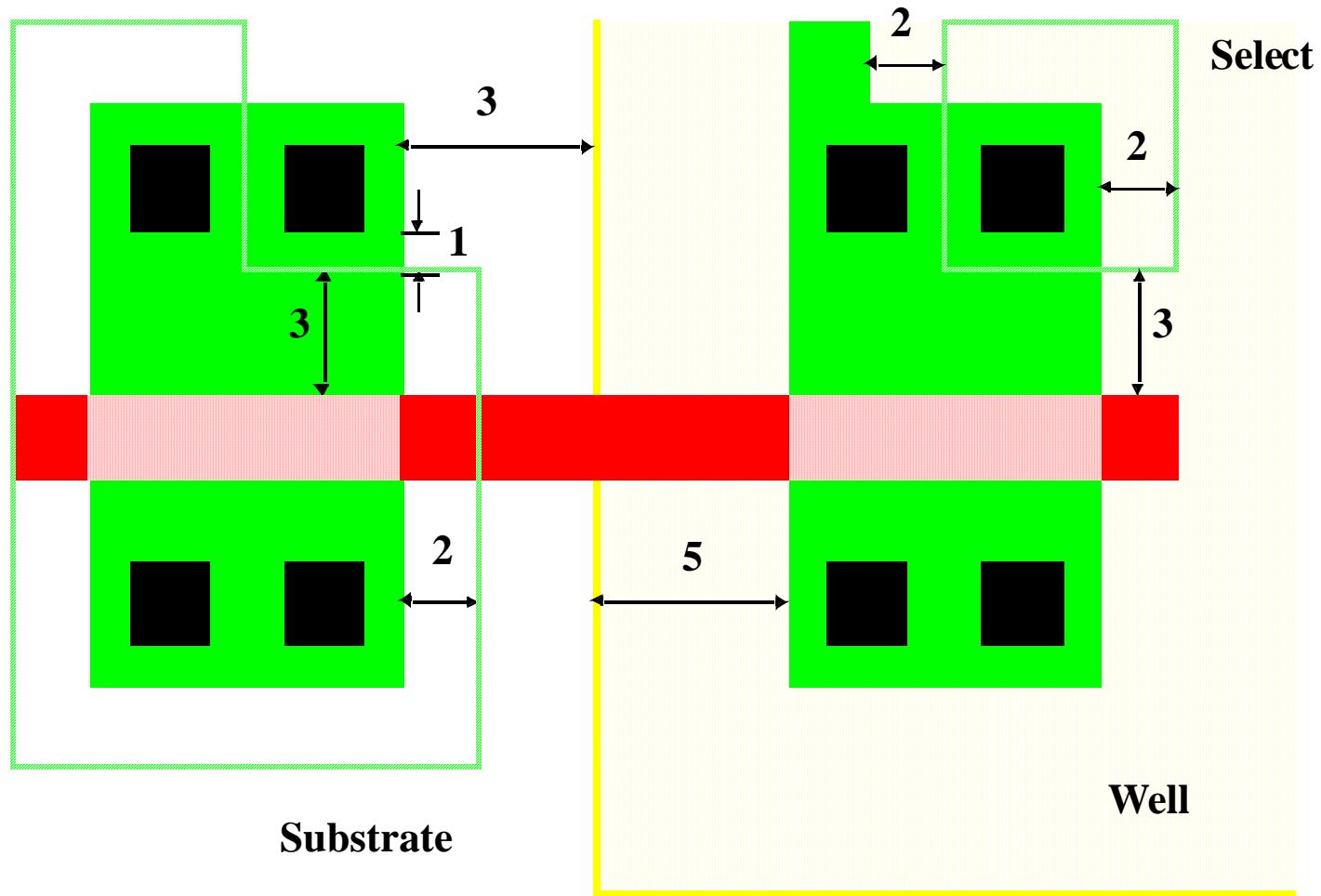
# Inter-Layer Design Rule Origins



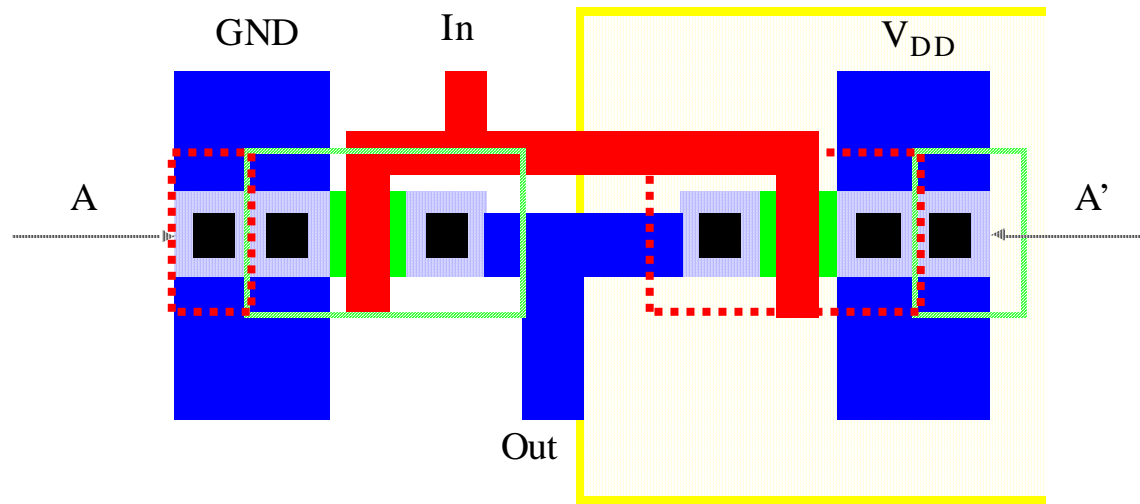
# Vias and Contacts Design Rules



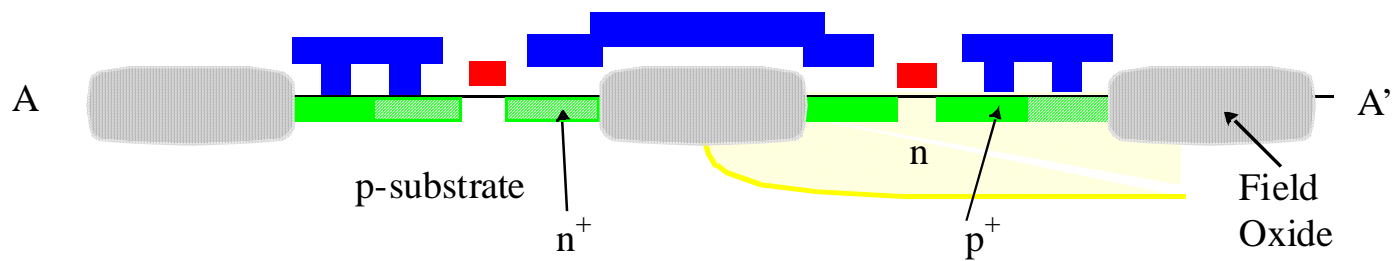
# *n+ or p+ Select Design Rules*



# Example: CMOS Inverter Layout

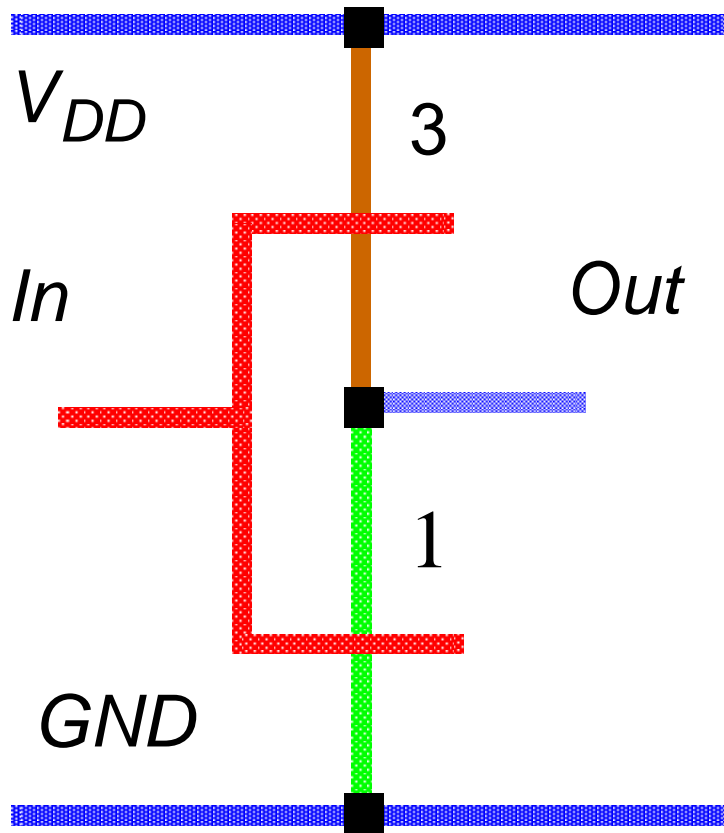


(a) Layout



(b) Cross-Section along A-A'

# CMOS Inverter Layout Sticks Diagram



- Dimensionless layout entities
- Only topology is important

Stick diagram of inverter

# ***Design Rules Note***

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- ❑ The book's process is NOT exactly the same as the one we will be using**
- ❑ In general the numbers in previous slides are not the numbers you will use, they are simply representative of what Design Rules are like**